

APPLICATION NO. 09/729513	CONT/PRIOR D	CLASS 250 673	SUBCLASS 412 105	ART UNIT 2881 2881	EXAMINER Fernandez
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APPLICANTS: Sanjay Yadur
 Bhanwar Singh
 Bryan Choo

TITLE: Use of scanning probe microscope for defect detection and repair

PTO-2040
12/99

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	_____ (Assistant Examiner) (Date)			NOTICE OF ALLOWANCE MAILED	
	_____ (Primary Examiner) (Date)			ISSUE FEE Amount Due Date Paid	
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